

In the Specification

Please amend the Abstract of the disclosure by inserting the underlined text ("_____") and removing the stricken text ("—").

A device testing system ~~comprising that has~~ automated test equipment (ATE), which
~~configured to interfaces~~ to a device under test (DUT). ~~The device testing system and logic~~
~~configured to~~ selects a test set of data comprising a plurality of test pairs, ~~the test pairs~~
indicative of DUT parameter values. ~~The system, the logic further configured to~~ selects a subset
of the plurality of test pairs from the test set of data ~~and to tests~~ the DUT via the ATE with a
portion of the selected subset based upon the test results of at least one of the test pairs.